Dec 13 04 01:35p

a cereby certify that this power and compared to the control to th



PATENT

Attorney Docket No. 006915 Plo RW Ref. No. APM/009-03

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of: Dan MAYDAN, et al.

Group Art Unit: 1763

Entitled: FABRICATION OF SILICON-ON-INSULATOR STRUCTURE USING PLASMA IMMERSION ION IMPLANTATION

Examiner: Unknown

Serial No.: 10/786,410

Filing Date: February 24, 2004

INFORMATION DISCLOSURE STATEMENT UNDER 37 CFR 1.97(b)

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

Attached hereto is Form PTO-1449 listing documents believed relevant to the subject application. It is respectfully requested each form be returned to the undersigned.

No representation is made that more pertinent material is not available or should not be considered by the Examiner. It is expected that the Patent and Trademark Office will independently conduct a complete search of appropriate art. Furthermore, no admission is being made that these documents are prior art, and applicant reserves the right to challenge any such consideration.

It is believed that this disclosure complies with the requirements of 37 CFR 1.56, 1.97, and 1.98, and the Manual of reason the Examiner considers otherwise, it is respectfully can be remedied.

BEST AVAILABLE COPY

A copy of each foreign patent document and/or non-patent literature is enclosed. Some of the documents may have markings on them. No significance is meant to be attached to the markings. These documents are not necessarily analogous art.

Dated.

Robert M. Wallace

Registration No. 29,119 Attorney for Applicants Customer No. 000044843

Respectfully submitted,

Robert M. Wallace Patent Attorney 2112 Eastman Avenue, Suite 102 Ventura, CA 93003 (805) 644-4035

Sheet 1 Of 1

FORM PTO-1449

U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

Amorney Docket No.: 006915 P10 Serial No.: 10/786,410

Applicant(s): Dan MAYDAN, et al.

LIST OF PRIOR ART CITED BY APPLICANT

(Use several sheets if necessary)

Filing Date: 02-24-2004

Group: 1763

	,		U. S. PATENTS			
Initials	Patent No	Issue Date	Name	Class	Subclass	Filing Date
.*	US-4,510,672	04-16-1985	YAKURA ET AL.	21	225	04-16-85
	US-4,914,500	04-03-1990	LIU ET AL.	357	67	04-03-90
	US-5,136,969	08-11-92	CHAPMAN	118	305	01-25-91
	US-5,840,589	11-24-1998	WARNER, JR. ET AL.	437	128	06-06-95
	US-5,918,140	06-29-199	WICKBOLDT ET AL.	438	535	06-16-97
	US-6,190,979 B1	02-20-2001	RADENS ET AL.	438	301	06-12-99
	US-6,312,999 B1	11-06-2001	CHIVUKULA ET AL.	438	303	03-29-01
	US-6,475,859 B1	11-05-2002	TEWS ET AL.	438	243	06-13-00
	US-6,500,741 B2	12-31-2002	BUCHANAN ET AL.	438	558	03-28-02
	US-6,506,653 B1	01-14-2003 ··	FURUKAWA ET AL.	438	305	03-13-00
	US-6,566,192	05-20-2003	LIN	438	243	02-07-02
	US 2002/0197806 A1	12-26-202	FURUKAWA ET AL.	438	305	08-16-02
	US 2003/0134469 A1	07-17-03	HORZEL ET AL.	438	249	01-27-03
	US 2004/0077157 A1	04-22-04	CHAKRAVARTHI ET	438	510	10-02-03
nitials	Oth	er Documents	Title, Author, Date, Pages, I	Etc., if kno	uwn)	

Other Documents (Title, Author, Date, Pages, Etc., if known) Huff, H. and Zeitzoff, Peter M., "An analytical look at vertical transistor structures", Solid State Technology, pp. 59-72, August 2004.

Examiner's Signature:

Date Considered:

Initial if reference was considered, whether or not citation with MPEP. Mark through citation if not considered. Include a copy of this citation form with your next correspondence to the Applicant(s).

COPY

Please acknowledge receip of the following:

USPTO Transmittal Form (1 page), Information Disclosure Statement under 37 CFR 1.97(b) (2 pages), Form PTO-1449 (1 page), one (1) cited non-patent literature document, return receipt postcard (2)

Applicant

: DAN MAYDAN ET AL.

Serial No.

: 10/786,410

Filed For : February 24, 2004 : FABRICATION OF SILICON-ON-INSULATOR

STRUCTURE USING PLAMSA IMMERSION

ION IMPLANTATION

Docket No.

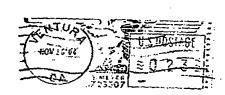
: 006915 USA P10

(APM/009-03)

Mailed

NOTENBER 18, 2004





ROBERT M. WALLACE 2112 Eastman Ave., Suite 102 Ventura, CA 93003

COPY

Ndeed Heal malled deal alled Joseph A

This Page is Inserted by IFW Indexing and Scanning Operations and is not part of the Official Record

BEST AVAILABLE IMAGES

Defective images within this document are accurate representations of the original documents submitted by the applicant.

Defects in the images include but are not limited to the items checked:
□ BLACK BORDERS
☐ IMAGE CUT OFF AT TOP, BOTTOM OR SIDES
☐ FADED TEXT OR DRAWING
BLURRED OR ILLEGIBLE TEXT OR DRAWING
☐ SKEWED/SLANTED IMAGES
COLOR OR BLACK AND WHITE PHOTOGRAPHS
GRAY SCALE DOCUMENTS
LINES OR MARKS ON ORIGINAL DOCUMENT
☐ REFERENCE(S) OR EXHIBIT(S) SUBMITTED ARE POOR QUALITY
OTHER:

IMAGES ARE BEST AVAILABLE COPY.

As rescanning these documents will not correct the image problems checked, please do not report these problems to the IFW Image Problem Mailbox.